

CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Accurate Instrument Repair, Inc.

27122 Burbank Foothill Ranch, CA 92610 (and satellite location as shown on the scope)

Fulfills the requirements of

ISO/IEC 17025:2017

and national standard

ANSI/NCSL Z540-1-1994 (R2002)

In the field of

CALIBRATION

This certificate is valid only when accompanied by a current scope of accreditation document. The current scope of accreditation can be verified at www.anab.org.

R. Douglas Leonard Jr., VP, PILR SBU

Expiry Date: 30 July 2025 Certificate Number: L2207





SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017 AND

ANSI/NCSL Z540-1-1994 (R2002)

Accurate Instrument Repair, Inc.

27122 Burbank Foothill Ranch, CA 92610 Anthony Sargent 949-454-2874

CALIBRATION

Valid to: July 30, 2025 Certificate Number: L2207

Length – Dimensional Metrology

Version 009 Issued: June 13, 2022

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Gage Blocks ²	(0.05 to 4) in	$(2.3 + 1.8L) \mu in$	Electro-mechanical
Gage Blocks	(5 to 20) in	(2+2L) µin	Comparison
Cylindrical Ring Gages ²	(0.04 to 14) in	$(4.4 + 4.1D) \mu in$	Labmaster Universal
Cylindrical Plug Gages ² High Accuracy	(0.1 to 6) in	$(5.8 + 3.8L) \mu in$	Lab Master Universal, Gage Blocks
Cylindrical Plug Gages ² (Plain)	(0.1 to 6) in	$(28 + 3.5L) \mu in$	Supermicrometer, Gage Blocks
Surface Plates ^{1,2} Overall Flatness	(21 to 140) in <i>DL</i>	8.5 √ <i>DL</i> μin	In accordance with Fed Spec GGG-P-463 using Leveling System
Local Area Flatness (repeat reading)	Up to 0.001 in	33 μin	Repeat Gage
Calipers 1,2	Up to 40 in	$(380 + 1.8L) \mu in$	Gage Blocks
Indicators 1,2	Up to 0.5 in Up to 1 in (1 to 12) in	30 μin 290 μin (320 + 0.9 <i>L</i>) μin	Indicator Calibrator, Height Master, Gage Blocks
Outside Micrometers 1,2	Up to 36 in	$(51 + 2.3L) \mu in$	Gage Blocks,
Inside Micrometers 1,2	Up to 24 in	$(350 + 0.3L) \mu in$	Ring Gages, Plug Gages





Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Height Gages ^{1,2}	Up to 40 in	$(62 + 2.7L) \mu in$	Gage Blocks, Surface Plate, Indicator
Super Micrometers, Bench Micrometers ¹	Up to 1 in	14 μin	Gage Blocks
Optical Comparators ¹ Linearity	Up to 16 in	120 µin	Glass Master, Magnification Scale
Magnification	Up to 12 in	690 μin	

Services performed at satellite location

26235 Enterprise Court Lake Forest, CA 92630

(all shipping, receiving and administrative functions are conducted at the main location)

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Current – Generate ¹	Up to 329 μA 330 μA to 3.29 mA (3.3 to 32.9) mA (33 to 329.9) mA 330 mA to 1.09 A (1.1 to 2.9) A (3 to 10.9) A (11 to 20.5) A	$0.2 \text{ nA/}\mu\text{A} + 27 \text{ nA}$ $0.11 \mu\text{A/mA} + 67 \text{ nA}$ $0.12 \mu\text{A/mA} + 0.29 \mu\text{A}$ $0.12 \mu\text{A/mA} + 2.7 \mu\text{A}$ $0.23 \text{ mA/A} + 49 \mu\text{A}$ $0.43 \text{ mA/A} + 91 \mu\text{A}$ 0.57 mA/A + 0.7 mA 1.5 mA/A + 1.1 mA	Fluke Multifunction Calibrator
DC Current – Generate Clamp Meters ¹	Up to 1 000 A	24 μΑ/Α + 64 μΑ	Multifunction Calibrator, Coil
DC Current – Measure ¹	Up to 10 mA (10.1 to 100) mA 100.1 mA to 1 A (1.1 to 3) A (3.1 to 100) A	0.57 μ A/mA + 2.4 μ A 0.57 μ A/mA + 7.3 μ A 1.1 μ A/mA + 0.14 mA 1.4 mA/A + 0.7 mA 0.047 % of reading	HP/Agilent Multimeter, Current Shunt





Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Source ¹	Up to 10 kHz Up to 329.9 μA 330 μA to 3.29 mA (3.3 to 32.9) mA (33 to 329.9) mA	9 nA/μA + 0.23 μA 5.8 μA/mA + 0.4 μA 2.3 μA/mA + 3.5 μA 2.3 μA/mA + 0.12 mA	Fluke Multifunction Calibrator
AC Current – Source ¹	Up to 5 kHz 330 mA to 2.9 A (3 to 10.9) A (11 to 20.5) A	6.9 mA/A + 1.2 mA 35 mA/A + 2.3 mA 35 mA/A + 5.3 mA	Fluke Multifunction Calibrator
AC Current – Measure ¹	Up to 3 A 10 Hz to 5 kHz	2.8 mA/A	HP/Agilent Multimeter
Resistance – Generate ¹ (Simulation)	Up to 10.9 Ω (11 to 32.9) Ω (33 to 109.9) Ω (110 to 329.9) Ω (0.33 to 1.09) $k\Omega$ (1.1 to 3.29) $k\Omega$ (3.3 to 10.9) $k\Omega$ (11 to 109.9) $k\Omega$ (0.11 to 1.09) $M\Omega$ (1.1 to 3.29) $M\Omega$ (3.3 to 10.9) $M\Omega$ (11 to 32.9) $M\Omega$ (11 to 32.9) $M\Omega$ (11 to 32.9) $M\Omega$ (10 to 329.9) $M\Omega$ (10 to 329.9) $M\Omega$	$\begin{array}{c} 50\mu\Omega/\Omega + 1.2m\Omega \\ 36\mu\Omega/\Omega + 1.8m\Omega \\ 33\mu\Omega/\Omega + 1.6m\Omega \\ 33\mu\Omega/\Omega + 2.3m\Omega \\ 34\mu\Omega/\Omega + 2.1m\Omega \\ 34m\Omega/k\Omega + 24m\Omega \\ 33m\Omega/k\Omega + 27m\Omega \\ 34m\Omega/k\Omega + 0.23\Omega \\ 38m\Omega/k\Omega + 2.2\Omega \\ 70\Omega/M\Omega + 37\Omega \\ 157\Omega/M\Omega + 52\Omega \\ 0.31k\Omega/M\Omega + 2.6k\Omega \\ 0.57k\Omega/M\Omega + 4.4k\Omega \\ 3.7k\Omega/M\Omega + 0.11M\Omega \\ 17k\Omega/M\Omega + 1.1M\Omega \\ \end{array}$	Fluke Multifunction Calibrator
Resistance – Measure ¹	Up to 100Ω 100.1Ω to $1 M\Omega$ $(1.1 \text{ to } 10) M\Omega$ $(10.1 \text{ to } 100) M\Omega$	$\begin{array}{c} 0.12 \text{ m}\Omega/\Omega + 4.6 \text{ m}\Omega \\ 0.13 \text{ m}\Omega/\Omega + 14 \text{ m}\Omega \\ 0.46 \text{ k}\Omega/M\Omega + 0.11 \text{ k}\Omega \\ 9.2 \text{ k}\Omega/M\Omega + 12 \text{ k}\Omega \end{array}$	HP/Agilent Multimeter
DC Voltage – Source ¹	Up to 329 mV (0.33 to 3.29) V (3.3 to 32.9) V (33 to 329) V (330 to 1 000) V	$\begin{array}{c} 0.2 \mu \text{V/mV} + 1.7 \mu \text{V} \\ 13.1 \mu \text{V/V} + 2.3 \mu \text{V} \\ 14 \mu \text{V/V} + 29 \mu \text{V} \\ 20.8 \mu \text{V/V} + 0.24 \text{mV} \\ 20.6 \mu \text{V/V} + 2.3 \text{mV} \end{array}$	Fluke Multifunction Calibrator





Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
	Up to 50 kHz		
	(1 to 32.9) mV	1.2 μ <mark>V/</mark> mV + 7 μV	
	(33 to 329) mV	0.4 μ <mark>V/m</mark> V + 11 μV	
AC Voltage – Source ¹	330 mV to 3.29 V	0.35 μ <mark>V/m</mark> V + 59 μV	Fluke Multifunction
Ac voltage – Source	(3.3 to 32.9) V	0.4 mV/V + 1.4 mV	Calibrator
	Up to 10 kHz		
	(33 to 329.9) V	$0.36 \mathrm{mV/V} + 7.8 \mathrm{mV}$	
	(330 to 1 020) V	$0.36 \mathrm{mV/V} + 1.4 \mathrm{mV}$	
	Up to 100 mV	$55 \text{ nV/mV} + 4.5 \mu\text{V}$	
	(0.1 to 1) V	$45 \text{ nV/mV} + 9.6 \mu\text{V}$	
DC Voltage – Measure ¹	(1.1 to 10) V	40 μV/V + 69 μV	HP/Agilent Multimeter
	(10.1 to 100) V	$54 \mu\text{V/V} + 0.78 \text{mV}$	
	(100.1 to 1 000) V	$53 \mu\text{V/V} + 12 \text{mV}$	
	Up to 750 V		
	(3 to 5) Hz	$12 \mu V/V + 3.5 \mu V$	
	(5 to 10) Hz	$4.5 \text{ mV/V} + 22 \mu\text{V}$	
AC Voltage – Measure ¹	10 Hz to 20 kHz	$1.2 \mathrm{mV/V} + 67 \mathrm{\mu V}$	HP/Agilent Multimeter
	(20 to 5 <mark>0) kHz</mark>	$2 \text{ V/V} + 45 \mu\text{V}$	
	(50 to 100) kHz	$7.9 \text{ mV/V} + 13 \mu\text{V}$	
	(100 to 300) kHz	$52 \text{ mV/V} + 1.9 \mu\text{V}$	
Electrical Simulation of Thermocouple Indicating Devices – Source/Measure ¹	Type J		
	(-210 to 1 200) °C	0.31 °C	
	Type K		
	(-100 to 1 000) °C	0.3 °C	Fluke Multifunction
	Type T		Calibrator
	(-150 to 400) °C	0.28 °C	
	Type E		
	(-100 to 1 000) °C	0.25 °C	







Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Capacitance – Source ¹			
(Simulation)			
10 Hz to 3 kHz	(0.19 to 3.29) nF	5.8 p <mark>F/n</mark> F + 12 pF	
10 Hz to 1 kHz	(3.3 to 10.9) nF	2.9 pF/nF + 12 pF	
10 Hz to 1 kHz	(11 to 109.9) nF	2.9 nF/nF + 0.12 nF	
10 Hz to 1 kHz	(110 to 329.9) nF	2.9 pF/nF + 0.34 nF	
(10 to 600) Hz	$(0.33 \text{ to } 1.09) \mu\text{F}$	$2.9 \text{ nF/}\mu\text{F} + 1.2 \text{ nF}$	
(10 to 300) Hz	$(1.1 \text{ to } 3.29) \mu\text{F}$	$3.3 \text{ nF/}\mu\text{F} + 2.5 \text{ nF}$	Fluke Multifunction
(10 to 150) Hz	(3.3 to 10.9) μF	$3 \text{ nF/}\mu\text{F} + 11 \text{ nF}$	Calibrator
(10 to 120) Hz	(11 to 32.9) μF	$4.7 \text{ nF/}\mu\text{F} + 34 \text{ nF}$	Calibrator
(10 to 80) Hz	$(33 \text{ to } 109.9) \mu\text{F}$	$5.3 \text{nF/} \mu \text{F} + 0.11 \mu \text{F}$	
(10 to 50) Hz	(110 to 329.9) μF	$5.3 \text{ nF/}\mu\text{F} + 0.34 \mu\text{F}$	
(10 to 20) Hz	(0.33 to 1.09) mF	$5.1 \mu\text{F/mF} + 1.3 \mu\text{F}$	
(10 to 6) Hz	(1.1 to 3.29) mF	$5.3 \mu F/mF + 3.6 \mu F$	
(10 to 2) Hz	(3.3 to 10.9) mF	$5.3 \mu\text{F/mF} + 12 \mu\text{F}$	
(10 to 0.6) Hz	(11 to 32.9) mF	8.9 μF/mF + 36 μF	
(10 to 0.2) Hz	(33 to 110) mF	$13 \mu\text{F/mF} + 0.12 \text{mF}$	

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Force ¹	Up to 100 kgf	0.000 012 % of reading + 22 µgf	NIST Class E Weights
Force -	Up to 500 lbf	0.01 % of reading + 0.012 lb	NIST Class F Weights
Torque Indicating Devices ¹	(0.002 to 1 000) lbf·ft	0.12 % of reading	Torque Calibration System
Pressure – Source ¹	(-2 to 2) psig Up to 29 psig Up to 50 psia (35 to 1 000) psig (300 to 30 000) psig	0.006 % of reading + 0.000 09 psi 0.006 % of reading + 0.000 13 psi 0.011 % of reading + 0.000 39 psi 0.011 % of reading + 0.007 7 psi 0.023 % of reading + 0.000 1 psi	
Mass Determination	Up to 200 g 50 g to 5 kg Up to 20 kg Up to 50 lb	0.000 29 % of reading + 29 μg 0.000 26 % of reading + 1.4 mg 0.000 23 % of reading + 18 mg 0.000 2 % of reading + 0.042 lb	ASTM E617 Class 1 Weights, Mass Comparators





Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
	Up to 200 g	0.000 3 % of reading + 39 μg	ASTM E617 Class 1
	(200 to 500) g	0.000 2 % of reading + 0.83 mg	weights and internal
Balances, Scales ^{1,3}	500 g to 30 kg	0.000 3 % of reading + 7.3 mg	procedure CP-0046.1
			utilized in the calibration of
	Up to 90 lb	0.000 05 % of reading + 0.000 5 lb	the weighing system.
			ASTM E617 Class 4
			weights and internal
Balances, Scales 1,3	Up to 80 kg	0.011 % of reading + 0.11 g	procedure CP-0046.1
			utilized in the calibration of
			the weighing system.
			NIST Class F weights
Scales 1,3			and internal procedure
	Up to 600 lb	0.011 % of reading + 0.001 5 lb	CP-0046.1 utilized in the
	- 1 A A		calibration of the
			weighing system.

Thermodynamic

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Humidity – Generate	(10 to 95) % RH	0.59 %RH	Two-Pressure Humidity Generator
Humidity – Measure ¹	(10 to 95) %RH	1.4 % RH	Humidity Indicator
	(-70 to 315) °C	0.001 % of reading + 0.095 °C	PRT, Sun Chamber
	0 °C	0.033 °C	PRT, VWR Liquid Bath
Electronic based Sensors and Mechanically-driven Thermometers 1	(-100 to 80) °C	0.001 % of reading + 0.029 °C	PRT, Hart/Lauda Liquid Bath
	(35 to 280) °C	0.005 6 % of reading + 0.019 ° C	PRT, Hart Liquid Bath
	(35 to 700) °C	0.004 9 % of reading + 0.021 ° C	PRT, Hart Dry Well
Temperature – Measure ¹	(-200 to 660) °C	0.005 % of reading + 0.02 °C	PRT
Infrared Thermometers ¹	(50 to 100) °C (100 to 200) °C (200 to 300) °C (300 to 400) °C (400 to 500) °C	2.4 °C 3.4 °C 4.5 °C 5.7 °C 6.5 °C	Fluke 2562 PRT Scanner w/ Omega RTD, Hart 9132 Blackbody $\epsilon = 0.95, \lambda = (8 \text{ to } 14) \mu \text{m}$





Time and Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Frequency – Generate ¹	45 Hz to 2 MHz	5.8 mHz/Hz + 3.7 mHz	Fluke Multifunction Calibrator
Frequency – Measure ¹	45 Hz to 300 kHz	0.12 Hz/kHz	HP/Agilent Multimeter

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 (*k*=2), corresponding to a confidence level of approximately 95%.

Notes:

- 1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
- 2. L = length in inches, D = diameter in inches, DL = diagonal length in inches.
- 3. The CMC for Scales and Balances is highly dependent upon the resolution of the unit under test. The CMC presented here does not include the resolution of the unit under test. The resolution will be included in the reported measurement uncertainty at the time of calibration.
- 4. This scope is formatted as part of a single document including Certificate of Accreditation No. L2207.



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